

Supplementary information
for
On the optical properties of Cr₂Ge₂Te₆ and its heterostructure

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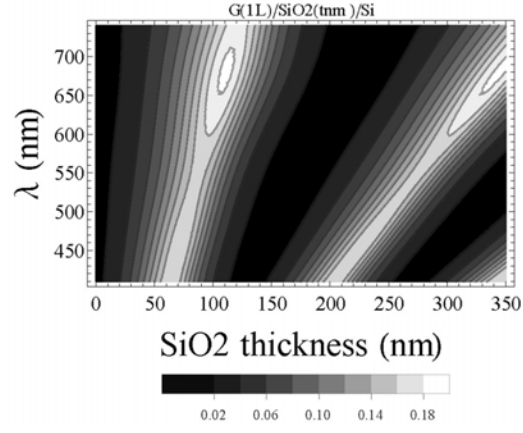


FIG. S1 Calculation on wavelength-dependent contrast ($R[n_1 = 1] - R[n_1 = n_{\text{flake}}]$) / $R[n_1 = 1]$ for Si/SiO₂/graphene(monolayer). The thickness of SiO₂ layer is varied from 0 nm to 350 nm.

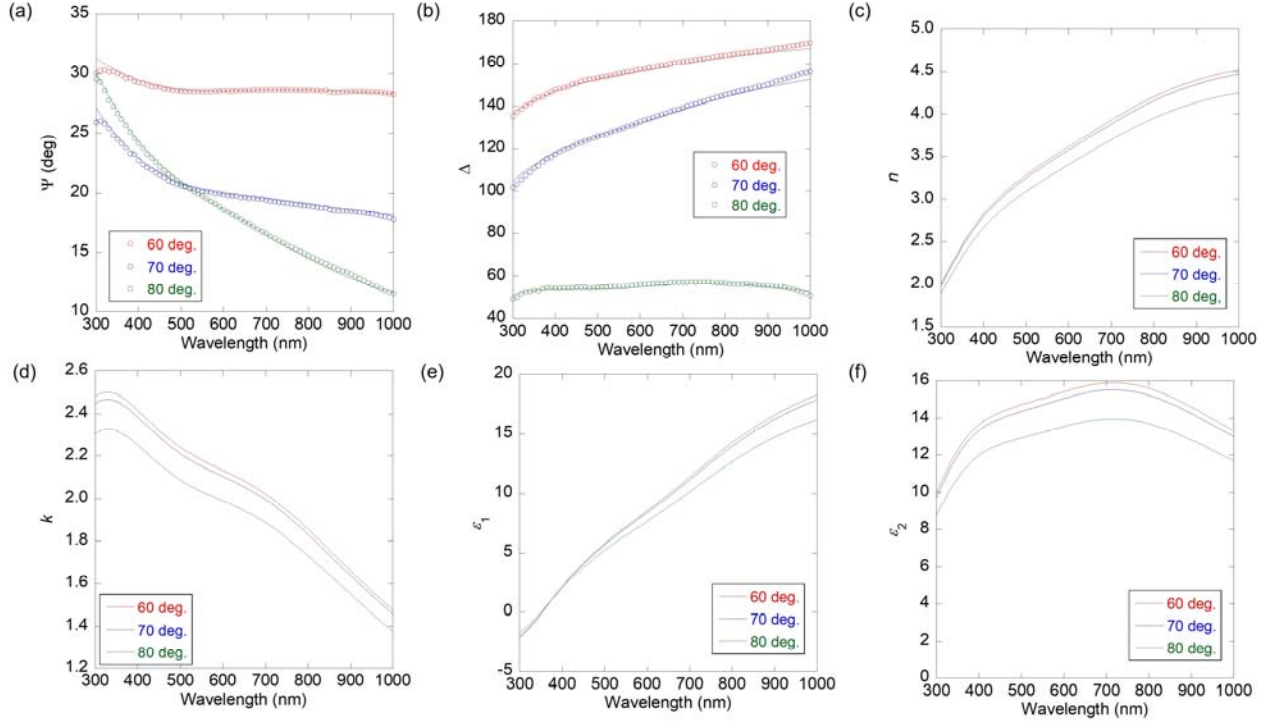


FIG. S2| (a,b) Ellipsometry characterization experiment for bulk $\text{Cr}_2\text{Ge}_2\text{Te}_6$ crystal. Wavelength dependence of Ψ (angle difference of the polarization between incident and detected light delay see the instruction on ellipsometry) and delta (the phase difference of the polarization of incident and reflected light). (c-f) Calculated n , k , ϵ_1 , ϵ_2 based on the model described in the text. n (k) represents real (imaginary) part of the refractive index. ϵ_1 (ϵ_2) represents real (imaginary) part of the dielectric function. 60 (70,80) deg. corresponds to incident angle (form the normal to the sample plane)